

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination FURUKAWA ET AL.	
		Examiner David Goodwin	Art Unit 2818	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2005/0087842	04-2005	Forbes, Leonard	257/617
*	B US-6,717,216	04-2004	Doris et al.	257/347
*	C US-6,884,667	04-2005	Doris et al.	438/164
*	D US-2004/0232490	11-2004	Akatsuka et al.	257/347
*	E US-2006/0060856	03-2006	Anderson et al.	257/066
*	F US-2005/0205936	09-2005	Grant et al.	257/347
*	G US-2005/0158921	07-2005	Akatsuka et al.	438/149
*	H US-2005/0045995	03-2005	Ieong et al.	257/627
*	I US-2004/0217391	11-2004	Forbes, Leonard	257/288
*	J US-2004/0150065	08-2004	Jan et al.	257/499
*	K US-6,630,699	10-2003	Wylie, Ian	257/288
*	L US-7,023,051	04-2006	Forbes, Leonard	257/347
*	M US-2005/0023616	02-2005	Forbes, Leonard	257/368

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
	U		
	V		
	W		
	X		

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.